501.41197CX1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): T. TAIRA

Serial No.: (not yet assigned)

Filed: September 26, 2003

For: FABRICATION METHOD OF SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND TESTING METHOD

REAFFIRMATION OF CLAIM FOR PRIORITY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

September 26, 2003

Sir:

Under the provisions of 35 USC §119 and 37 CFR §1.55, Applicants hereby claim the right of priority based on Japanese Patent Application No. 2001-075671, filed in Japan on March 16, 2001.

The certified copy of the above-referred to Japanese Patent Application was filed on March 14, 2002 in prior application Serial No. 10/096,801, filed March 14, 2002.

Respectfully submitted,

Melvin Kraus
Registration No. 22,466
ANTONELLI, TERRY, STOUT & KRAUS, LLP

MK/cee
(703) 312-6600